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Power quality measurement in power supply systems –
Part 2: Functional tests and uncertainty requirements
<http://standards.iteh.ai>

Mesure de la qualité de l'alimentation dans les réseaux d'alimentation –
Partie 2: Essais fonctionnels et exigences d'incertitude
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NORME INTERNATIONALE



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STANDARD PREVIEW
Part 2: Functional tests and uncertainty requirements
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This second edition cancels and replaces the first edition published in 2013. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) test procedures for RVC and current have been added;
- b) mistakes have been fixed.

This bilingual version (2017-11) corresponds to the monolingual English version, published in 2017-03.

The text of this standard is based on the following documents:

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Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

The French version of this standard has not been voted upon.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

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INTRODUCTION

Power quality is more and more important worldwide in power supply systems and is generally assessed by power quality instruments.

This part of IEC 62586 specifies functional and uncertainty tests intended to verify the compliance of a product to class A and class S measurement methods defined in IEC 61000-4-30.

This document therefore complements IEC 61000-4-30.

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POWER QUALITY MEASUREMENT IN POWER SUPPLY SYSTEMS –

Part 2: Functional tests and uncertainty requirements

1 Scope

This part of IEC 62586 specifies functional tests and uncertainty requirements for instruments whose functions include measuring, recording, and possibly monitoring power quality parameters in power supply systems, and whose measuring methods (class A or class S) are defined in IEC 61000-4-30.

This document applies to power quality instruments complying with IEC 62586-1.

This document can also be referred to by other product standards (e.g. digital fault recorders, revenue meters, MV or HV protection relays) specifying devices embedding class A or class S power quality functions according to IEC 61000-4-30.

These requirements are applicable in single-, dual- (split phase) and 3-phase AC power supply systems at 50 Hz or 60 Hz.

It is not the intent of this document to address user interface or topics unrelated to device measurement performance. **iTeh STANDARD PREVIEW (standards.iteh.ai)**

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2 Normative references

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IEC 61000-2-4, *Electromagnetic compatibility (EMC) – Part 2-4: Environment – Compatibility levels in industrial plants for low-frequency conducted disturbances*

IEC 61000-4-7, *Electromagnetic compatibility (EMC) – Part 4-7: Testing and measurement techniques – General guide on harmonics and interharmonics measurements and instrumentation, for power supply systems and equipment connected thereto*

IEC 61000-4-15, *Electromagnetic compatibility (EMC) – Part 4-15: Testing and measurement techniques – Flickermeter – Functional and design specifications*

IEC 61000-4-30:2015, *Electromagnetic compatibility (EMC) – Part 4-30: Testing and measurement techniques – Power quality measurement methods*

IEC 62586-1:2013, *Power quality measurement in power supply systems – Part 1: Power quality instruments (PQI)*

ISO/IEC Guide 98-3:2008, *Uncertainty of measurement – Part 3: Guide to the expression of uncertainty in measurement (GUM:1995)*

3 Terms, definitions, abbreviated terms, notations and symbols

For the purposes of this document, the terms and definitions given in IEC 61000-4-30 and the following apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>

3.1 General terms and definitions

3.1.1

limit range of operation

extreme conditions that a measuring instrument can withstand without damage and degradation of its metrological characteristics when it is subsequently operated within its rated operating conditions

Note 1 to entry: The measuring instrument should be able to function within the limit range of operation.

3.1.2

rated range of operation

range of values of a single influence quantity that forms a part of the rated operating conditions

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Note 1 to entry: Uncertainty should be met within the rated range of operation.

3.2 Terms and definitions related to uncertainty

[IEC 62586-2:2017](#)

3.2.1 <https://standards.itech.ai/catalog/standards/sist/98f3d5e2-030e-45d4-a94d-3b5584797f52/iec-62586-2-2017>

intrinsic uncertainty uncertainty of a measuring instrument when used under reference conditions

Note 1 to entry: In this document, it is a percentage of the measured value defined in its rated range and with all influence quantities under reference conditions, unless otherwise stated.

[SOURCE: IEC 60359:2001, 3.2.10, modified – Note 1 to entry has been added.]

3.2.2

influence quantity

quantity which is not the subject of the measurement and whose change affects the relationship between the indication and the result of the measurement

Note 1 to entry: Influence quantities can originate from the measured system, the measuring equipment or the environment [IEV].

Note 2 to entry: As the calibration diagram depends on the influence quantities, in order to assign the result of a measurement it is necessary to know whether the relevant influence quantities lie within the specified range [IEV].

Note 3 to entry: An influence quantity is said to lie within a range C' to C'' when the results of its measurement satisfy the relationship: $C' \leq V - U < V + U \leq C''$.

[SOURCE: IEC 60359:2001, 3.1.14]

3.2.3

variation

variation due to a single influence quantity

difference between the value measured under reference conditions and any value measured within the rated operating range (for this specific influence quantity)